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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular, the different approval criteria needed for the different types of ISO document should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2 (see www.iso.org/directives).

ISO draws attention to the possibility that the implementation of this document may involve the use of (a) patent(s). ISO takes no position concerning the evidence, validity or applicability of any claimed patent rights in respect thereof. As of the date of publication of this document, ISO ~~had~~ had not received notice of (a) patent(s) which may be required to implement this document. However, implementers are cautioned that this may not represent the latest information, which may be obtained from the patent database available at www.iso.org/patents. ISO shall not be held responsible for identifying any or all such patent rights.

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For an explanation of the voluntary nature of standards, the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the World Trade Organization (WTO) principles in the Technical Barriers to Trade (TBT), see www.iso.org/iso/foreword.html.

This document was prepared by Technical Committee ISO/TC 172, *Optics and photonics*, Subcommittee SC 3, *Optical materials and components*.

A list of all parts in the ISO 6760 series can be found on the ISO website.

Any feedback or questions on this document should be directed to the user's national standards body. A complete listing of these bodies can be found at www.iso.org/members.html.

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Introduction

Optical glass is widely used in optical devices such as cameras, telescopes, and microscopes, and its refractive index is measured by the minimum deviation method (ISO 21395-1^[4]) and the V-block refractometer method (ISO 21395-2^[5]). Here, when designing an optical apparatus that requires high resolution, it is necessary to consider the temperature change of the refractive index of the optical glass in the usage environment. This document proposes a method for measuring the temperature coefficient of refractive index of optical glass with high accuracy.

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Optics and photonics — Test method for temperature coefficient of refractive index of optical glasses

Part 2: Interferometric method

1 Scope

This document specifies a test method for the temperature coefficient of refractive index of optical glass using interferometry. Temperature changes in optical glass lead to changes in the optical path length. The change in optical path length can be measured with an interferometer using the number of cycles of light/dark change of the interference stripe. This document defines a test method to measure the amount of change in the refractive index when the temperature of the specimen is changed continuously.

The intended temperature range for the specified measurement method is an arbitrary range.

The intended wavelength range for the specified measurement method is 365 nm to 1 014 nm.

The intended accuracy for the specified measurement method is within 1×10^{-6} K⁻¹.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

There are no normative references in this document.

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- ISO-Online browsing platform: available at <https://www.iso.org/obp>
- IEC-Electropedia: available at <https://www.electropedia.org/>

3.1 temperature coefficient of refractive index

ratio of refractive index change to temperature change at a selected wavelength

Note 1 to entry: Similar to ISO 9802^[2].

[SOURCE: ISO 9802:2022^[3], 3.4.2.3, 3.4.2.4, modified — term and definition slightly reworded.]

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3.2 temperature coefficient of absolute refractive index

ratio of refractive index change in vacuum to temperature change at a selected wavelength

[SOURCE: ISO 9802:2022, 3.4.2.3, modified — term reworded.]

3.3 temperature coefficient of relative refractive index

ratio of refractive index change at an air pressure of 1,013 25 × 10⁵ Pa and a relative humidity of 0 % to temperature change at a selected wavelength

[SOURCE: ISO 9802:2022, 3.4.2.4, modified — term reworded and "0,101 33 × 10⁶ Pa" and "0 % humidity" added.]

Note 1 to entry: This definition of Δn_{rel}/ΔT is for a specific pressure and humidity. Δn_{rel}/ΔT can be calculated for any other pressure and humidity by understanding the index of air in those conditions.

3.4 thermal chamber

chamber where the temperature of the specimen can be changed and/or maintained to a preset temperature

4 Principle

The temperature coefficient of refractive index is calculated in either Formula (1) or Formula (2) obtained by Annex C. Annex C. The derivation of these formulae is described in Annex C. Annex C. For a calculation method for obtaining the relative refractive index of glass at an arbitrary temperature and relative humidity, see Annex B. Annex B.

Δn_{abs}/ΔT = 1/2 * (f * λ / (L * ΔT)) - α₁ * n_{abs} (1)

Δn_{abs}/ΔT = 1/2 * (f * λ / (L * ΔT)) - α₁ * n_{rel} (2)

Δn_{abs}/ΔT = 1/2 * (f * λ / (L * ΔT)) - α₁ * n_{abs} (1)

Δn_{abs}/ΔT = 1/2 * (f * λ / (L * ΔT)) - α₁ * n_{rel} (2)

where

Δn_{abs}/ΔT is the temperature coefficient of absolute refractive index of specimen (K⁻¹);

1/2 is interferometer scale factor of double-path interferometers;

λ is the wavelength of the refractive index temperature coefficient measurement (m);

L is the measurement specimen length (m);

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- f is the number of cycles of light/dark change of interference fringes associated with changes in optical path length of the specimen corresponding to ΔT ;
- ΔT is the specimen temperature difference (K);
- n_{abs} is the absolute refractive index of the specimen;
- n_{rel} is the relative refractive index of the specimen;
- α is the linear expansion coefficient of the specimen (K^{-1}).

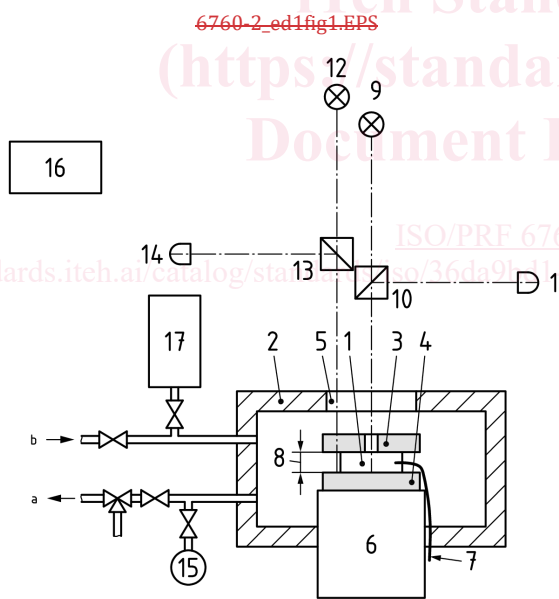
5 Measuring apparatus

5.1 General

The measuring equipment shall be in accordance with the requirements in 5.2 to 5.9.

- a) a) For measuring equipment, use the Fizeau-interference measurement principle in which the measured sample itself constitutes the interference space.
- b) b) The resolution to read the number of cycles of light and dark changes in the interference space. The resolution shall be 1/10 cycle or less.

Figure 1 shows an example of a schematic diagram of the measuring equipment.



Key

- | | |
|-------------------------|--|
| 1 specimen | 11 detector for optical path length change of the specimen measurement |
| 2 thermal chamber shell | 12 light source for expansion measurement |
| 3 transmission flat | 13 beam splitter for expansion measurement |
| 4 reference flat | 14 detector for expansion measurement |

Figure 2. The contact points of the specimen and the flat plate are on the same plane. The flat plate geometry is described in Annex F.

The required accuracies of the two flat plates are as follows:

- a) The transmission flat plate and reference flat plate shall be made of quartz glass or extremely low expansion glass ceramics, where both sides of which have been polished with a wedge angle of approximately 6 arc min ($0,1^\circ$).
- b) The flatness of the surface used for the interference action shall be $\lambda/2$ or less ($1/2$ of the measurement wavelength of the linear expansion coefficient).
- c) There shall be a hole in the centre of the transmission flat plate to secure the optical path for measurement of change in the optical path length of the specimen.
- d) The back surface not involved in interference of the reference flat plate may be ground glass surface without polishing. In this case, the wedge angle of the reference flat plate is not required.
- e) A suitable method should be used to ensure that reflections from the rear surface of the reference flat plate do not cause confusion with desired interference pattern. For example, there are sanding and donut-shaped processing by making a hole in the relevant position.

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